

First prototype production of DJ-LGAD: a new approach to high granularity LGADs

45° RD50 Workshop (2022, Sevilla, Spain)
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LGAD arrays

- Granularity is a current limitation for LGADs
- Due to high fields in the multiplication layer the pads need electrical insulation
 - Protection structure: Junction Termination Extension (JTE)
 - Causes inter pad (IP) gap to 50-150 μm , also changes with applied bias voltage
 - Limits LGAD granularity to mm scale
- However 50 μm pitch (and lower) is required for next generation colliders and 4D tracking
 - At least same level as the ATLAS new inner tracker (ITk) needed
- Several possible solutions are being investigated by the community
 - AC-coupled (RSD) LGADs, Trench insulated LGADs, inverted LGADs...

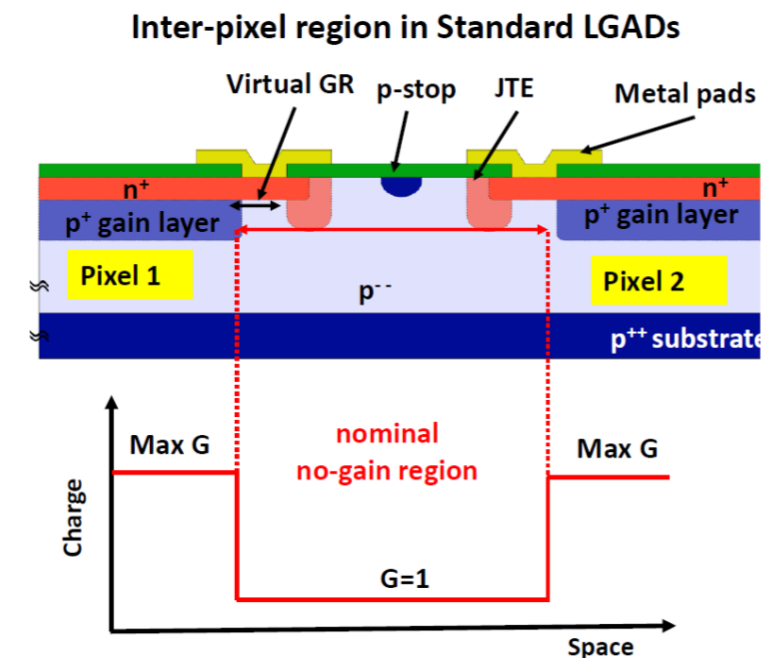
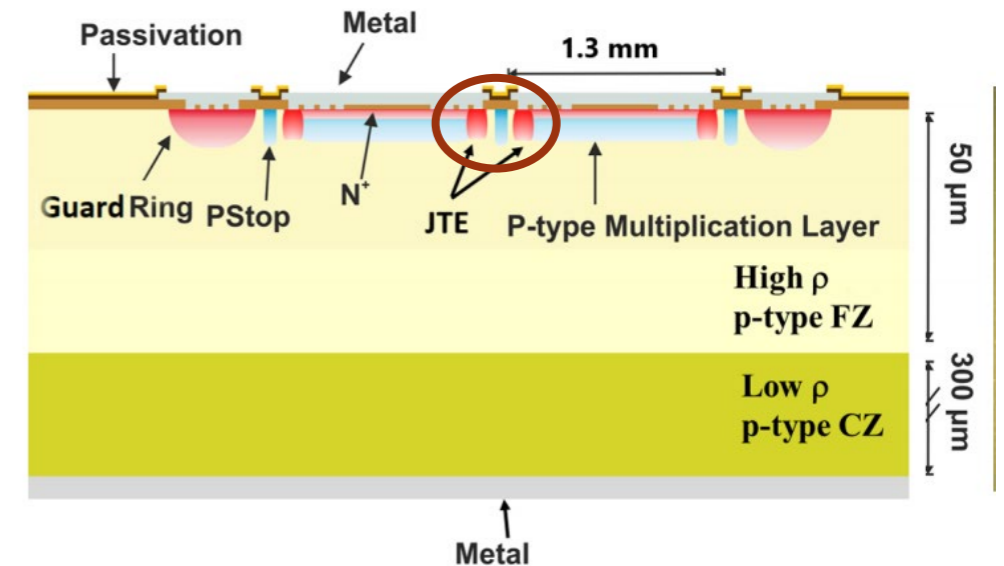
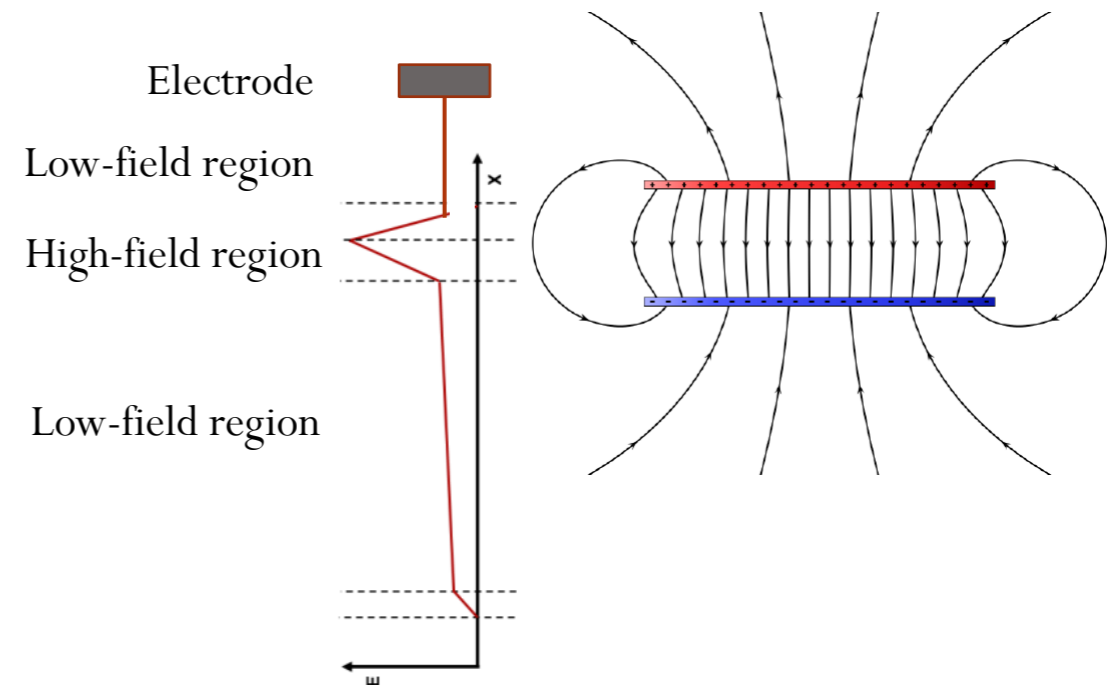
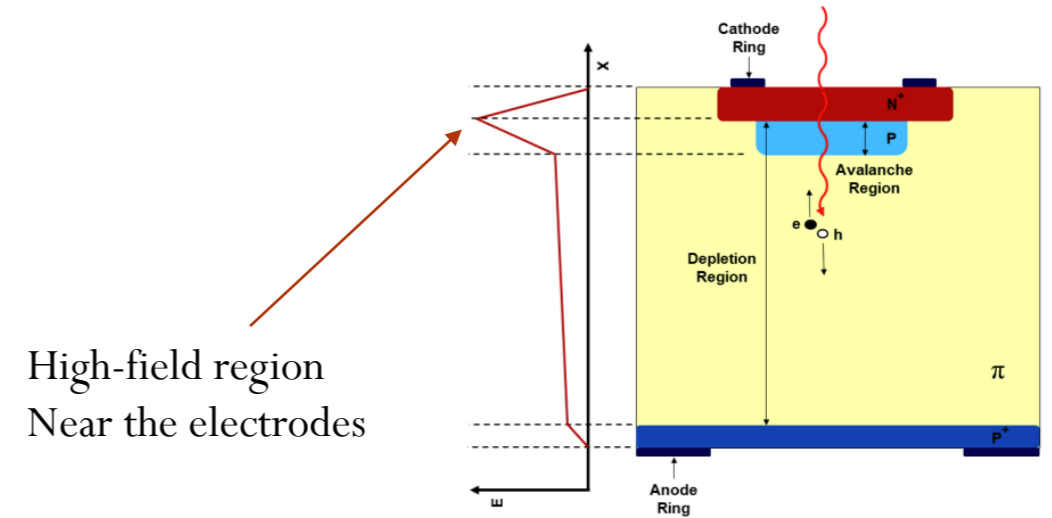


Diagram credit: FBK, Trento, Italy

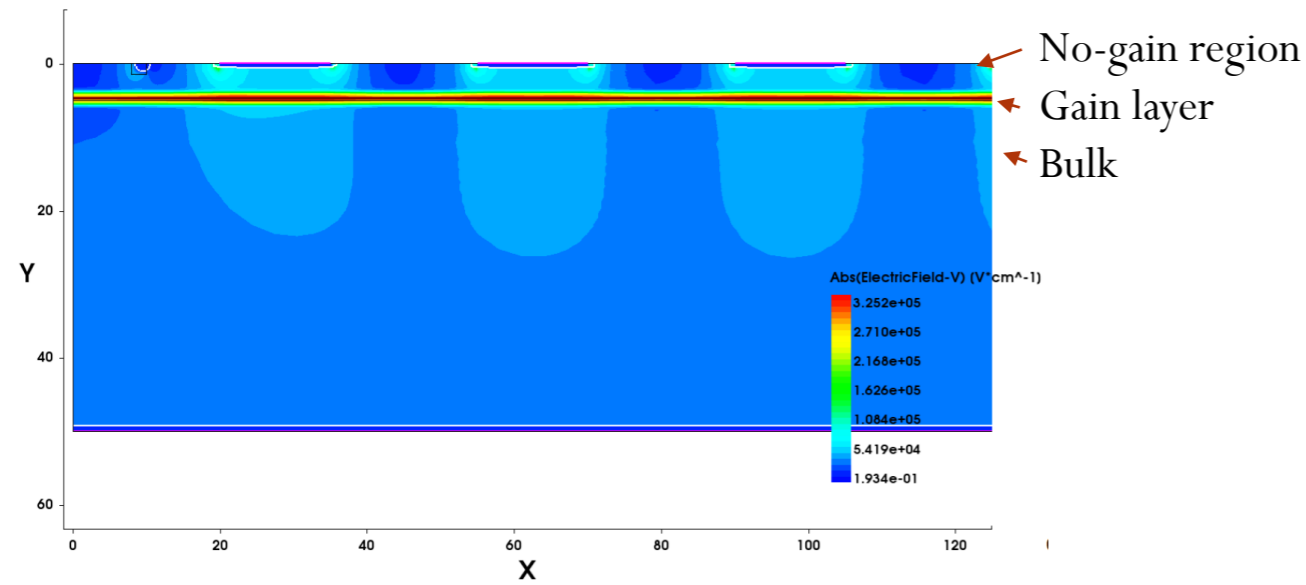
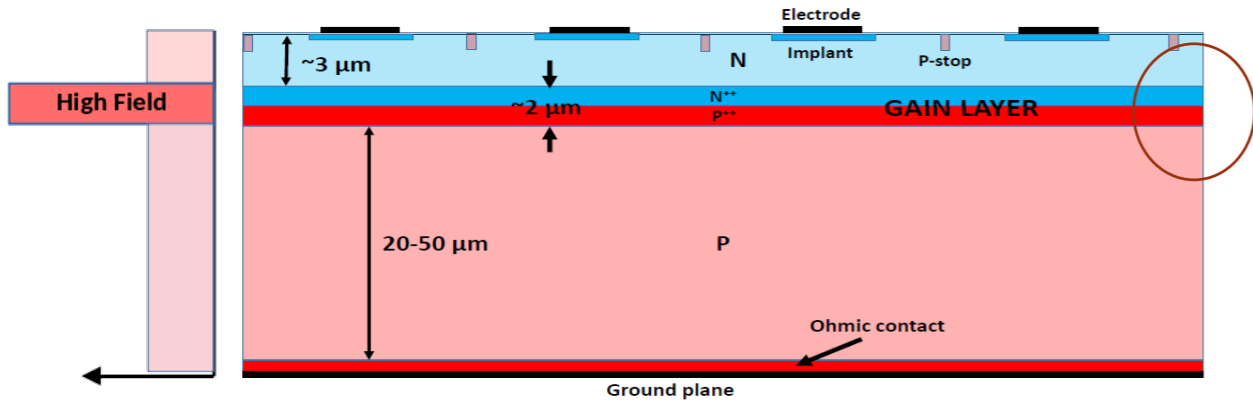
A new approach: deep junction

- Granularity limit is caused by high field near the electrodes
 - **What if the field is kept low while maintaining gain?**
- Basic inspiration is that of the capacitive field:
 - Large between plates, but surrounded by low-field region beyond the plates
- Use symmetric P-N junction to act as an effective capacitor
- Localized high field in junction region creates impact ionization
- Bury the P-N junction so that fields are low at the surface, allowing conventional granularity
- → **“Deep Junction” LGAD (DJ-LGAD)**
- Concept presented at TREDI 2020
 - <https://indico.cern.ch/event/813597/contributions/3727775/>

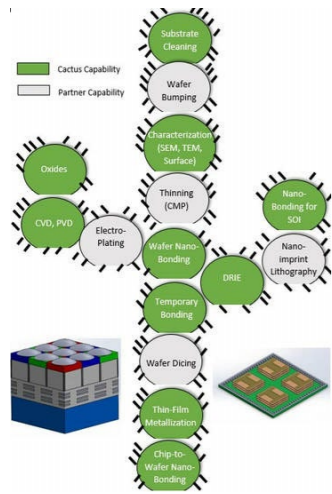


DJ-LGAD

Termination of the gain layer was studied in the first production

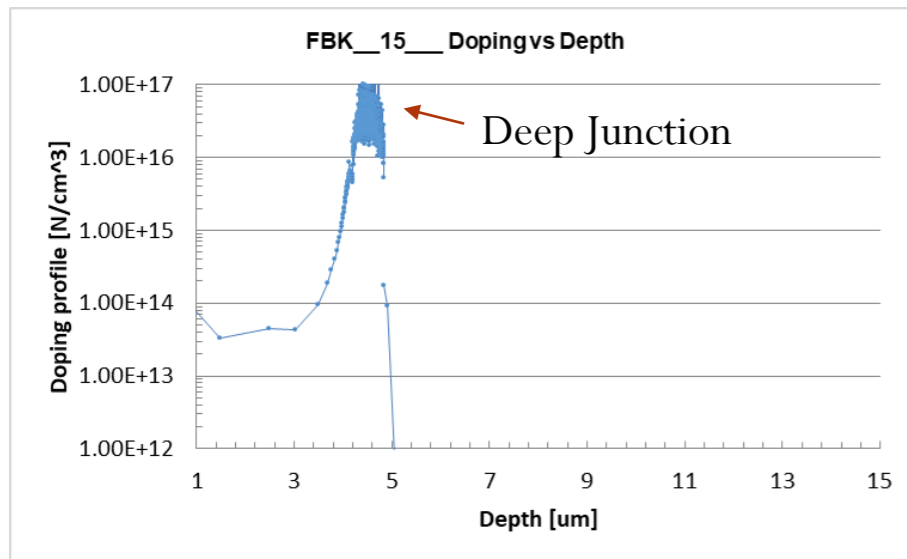


- **P++ gain layer is paired with a N++ layer that lowers the field**
 - Junction is buried $\sim 5 \mu\text{m}$ inside the detector
- Tuning of N+ and P+ parameters important
 - Low field outside of the electrodes while maintaining sufficient gain
 - No need for a JTE
 - Different termination of the gain layer designed
- DJ-LGAD design studied with TCAD Sentaurus
- First production in collaboration with BNL and CACTUS materials is ready!
- **Patent WO2021087237A1**
 - C. Gee, S. M. Mazza, B. Schumm, Y. Zhao
 - <https://patents.google.com/patent/WO2021087237A1/en>



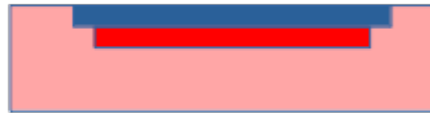
Fabrication of the device

- Two productions funded by phase I SBIR were recently completed
 - UCSC in collaboration with **Cactus Material** (AZ) and **BNL**
 - Founded by DoE SBIR “A New Approach to Achieving High Granularity in Low Gain Avalanche Detectors” (34b)
 - Phase I finished, Phase II started
- **First prototype using Epitaxial layer growth**
 - Deep layer implanted and the buried by the growth
 - The prototypes breaks down early in voltage
 - However, deep junction placement was successful
 - Signal observed with high ionizing particles (alpha)
- **Second prototype using w2w bonding**
 - The production was successful with many wafers reaching completion
 - Some wafers had issues with processing after w2w bonding procedure
 - Standard PiNs but with deep junction work as well
 - High current for most prototypes to be addressed in the next production



Fabrication process for prototype run 1 and 2

Gain Layer Implantation
Similar to Conventional LGAD, but
with higher energy



Epitaxial growth of high
resistivity N type layer



Deposit electrodes and implants



Gain Layer Implantation
on N and P type substrate



Wafer-wafer bonding

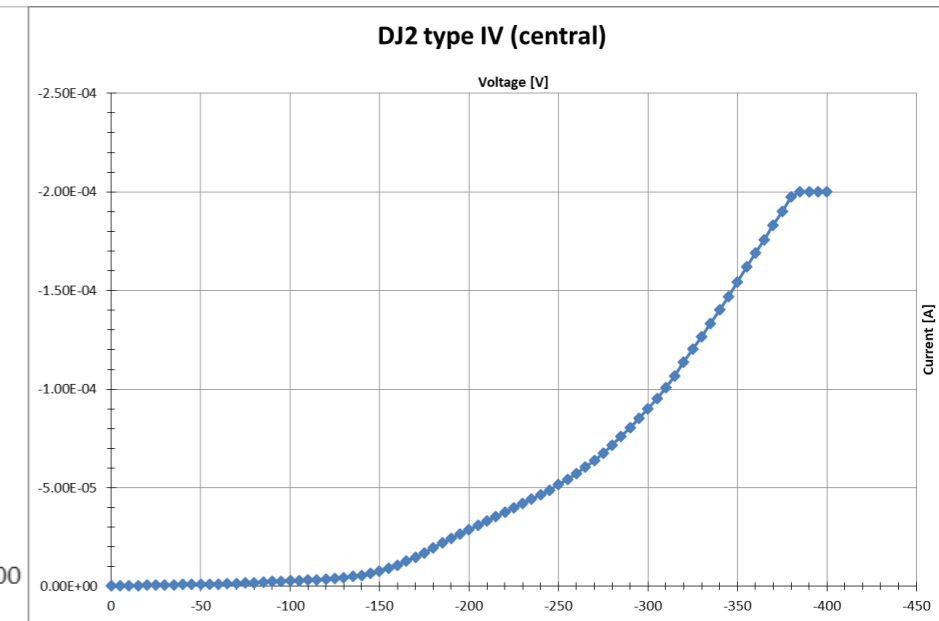
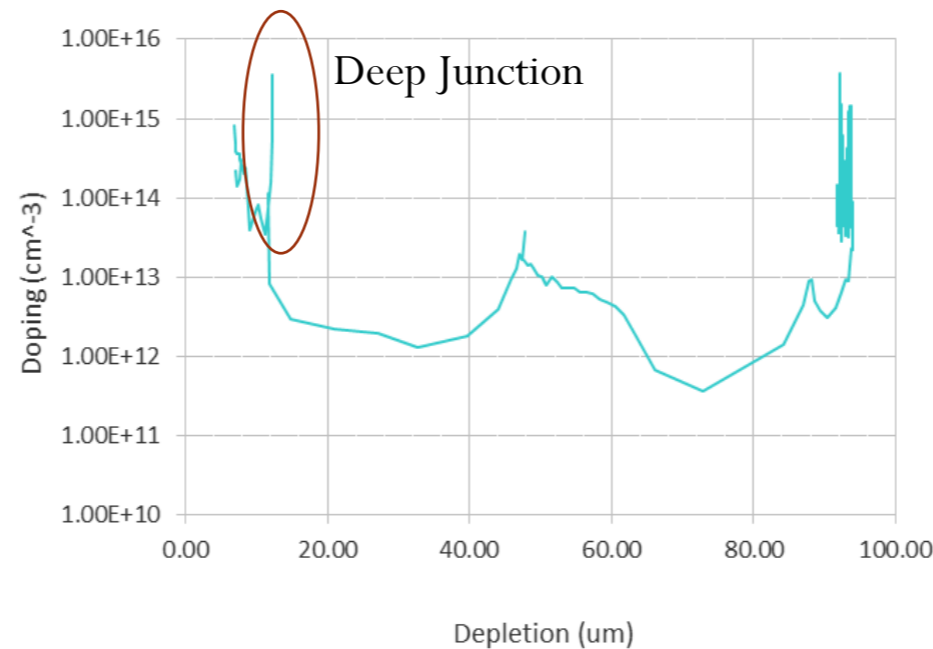
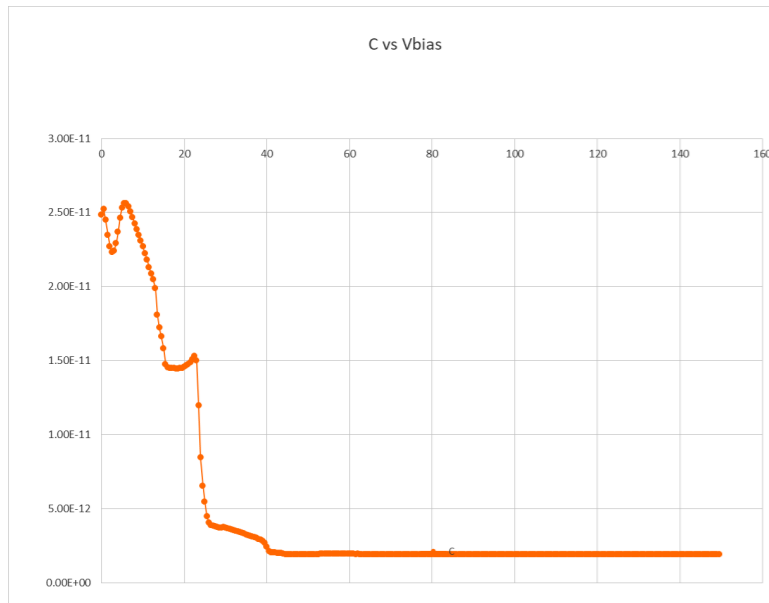
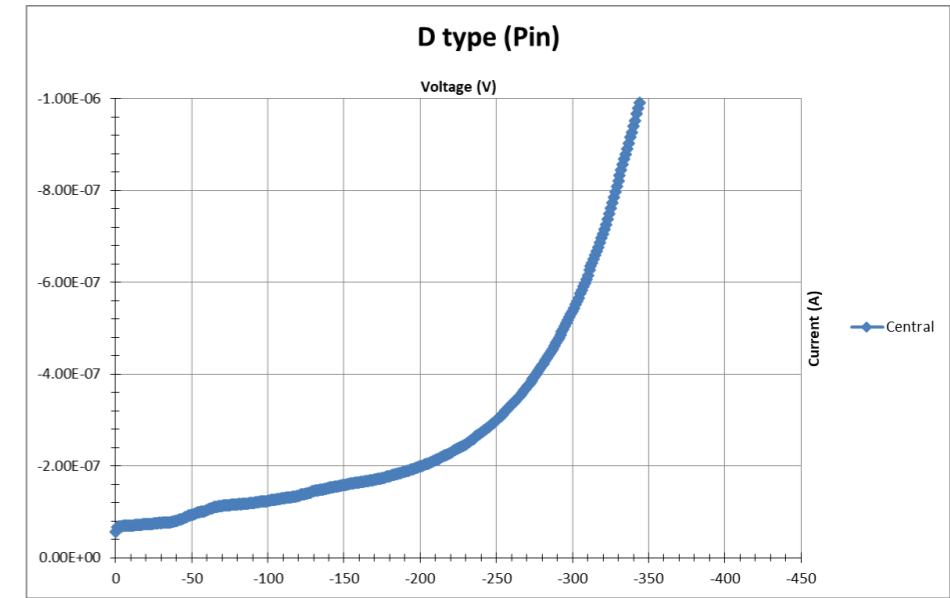


In the production there are two different
ways to terminate the junction: symmetric
and asymmetric

2x1 arrays were also produced and show
minimal IP gap

DJ-LGAD 2nd prototype run

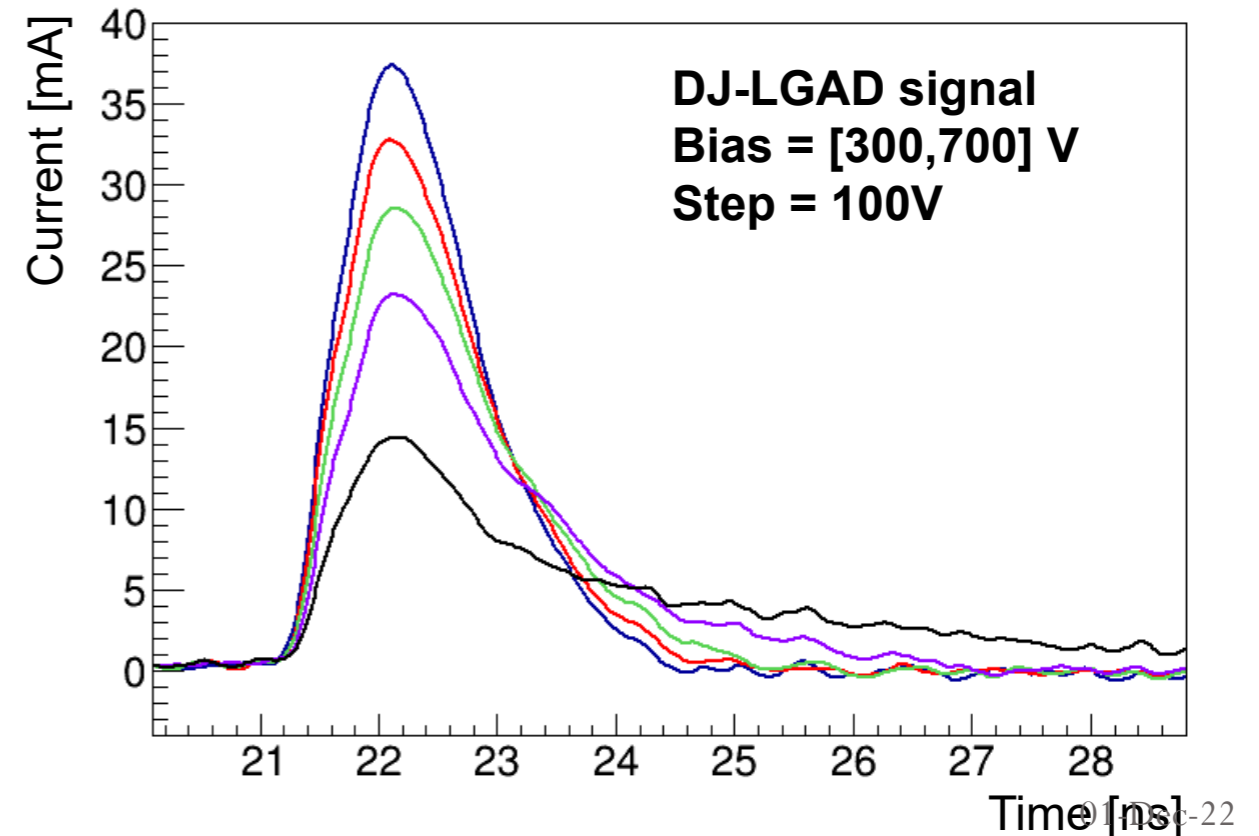
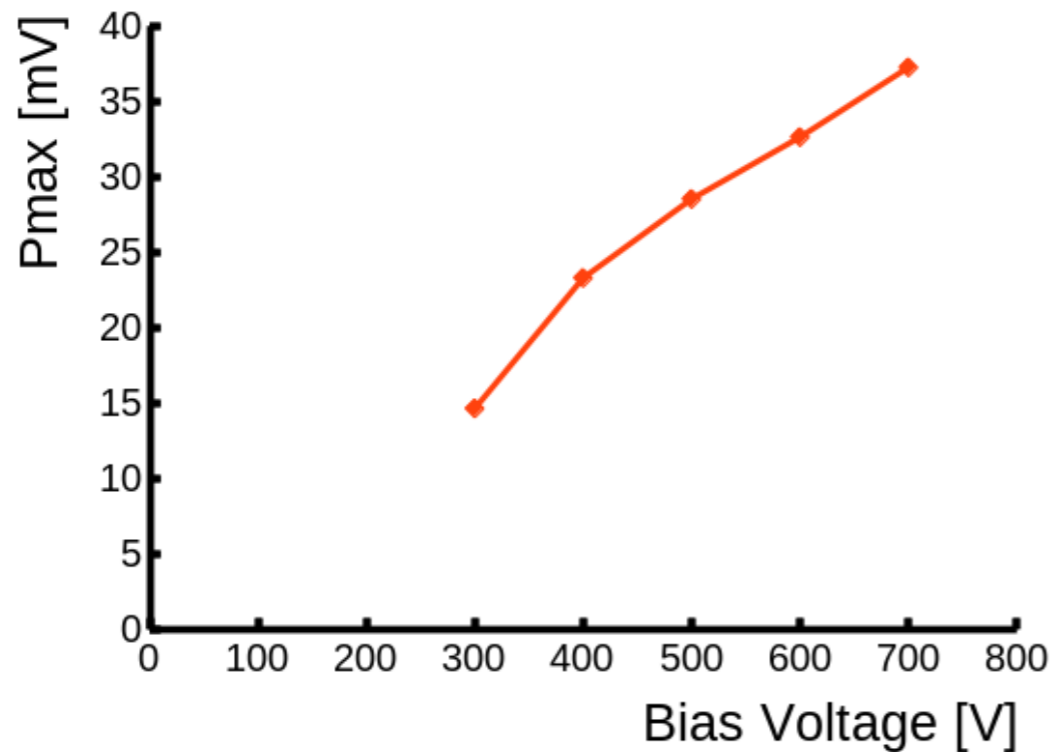
- D-type, standard PiN with deep junction, Current <1uA
- DJ-type, deep junction ending below the active area, High current (100s uA)
 - The sensor is also very noisy, not usable
- DJ2-type, deep junction ending under the Guard ring
 - Manageable current (10s uA), BV seems to be very high
 - CV shows deep junction structure, thickness seems higher than expected
- DJ3-type, 2x1 array, termination as DJ2, Manageable current (10s uA)



Charge collection studies

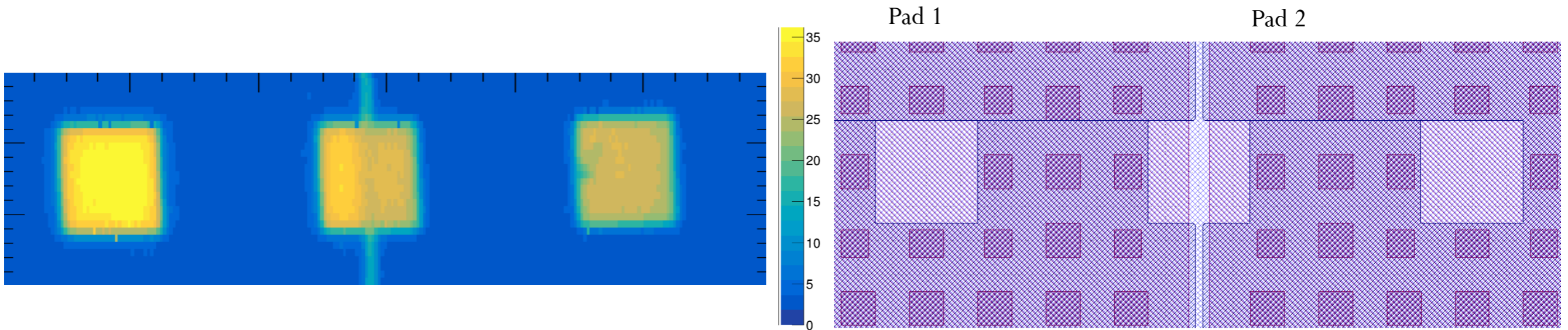
Data taken by Miguel Godoy

- Sensor mounted on UCSC 1ch and 4ch board, test with Sr90 source with know trigger sensor to study MiP response
 - Read out by fast oscilloscope, trigger on the trigger sensor
- **Rise time ~ 580 ps, similar to a typical 50-60um LGAD, Breakdown >700 V**
- **Measured gain of ~ 3 to 5**
 - Lower than conventional LGAD
 - Optimization of the gain layer doping is required for future prototype



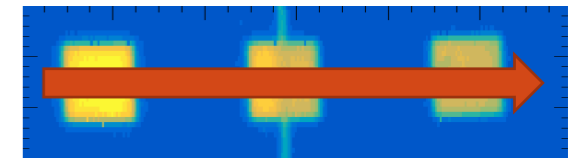
Laser studies

- **DJ-LGAD 2x1 array prototype is studied with IR Laser scan**
 - Digitized by fast scope, laser spot size is 10-20 μm
- Pmax values in terms of the laser beam location are shown for sum of channels
 - Sensors have 3 open areas in the metal, one in each pad and in between pads
 - In the scan the blue low signal region corresponds to the metal
 - The sum of the two signals is more or less constant on the sensor (no gain loss in between pads)



Laser studies

Data taken by Yuzhan Zhao

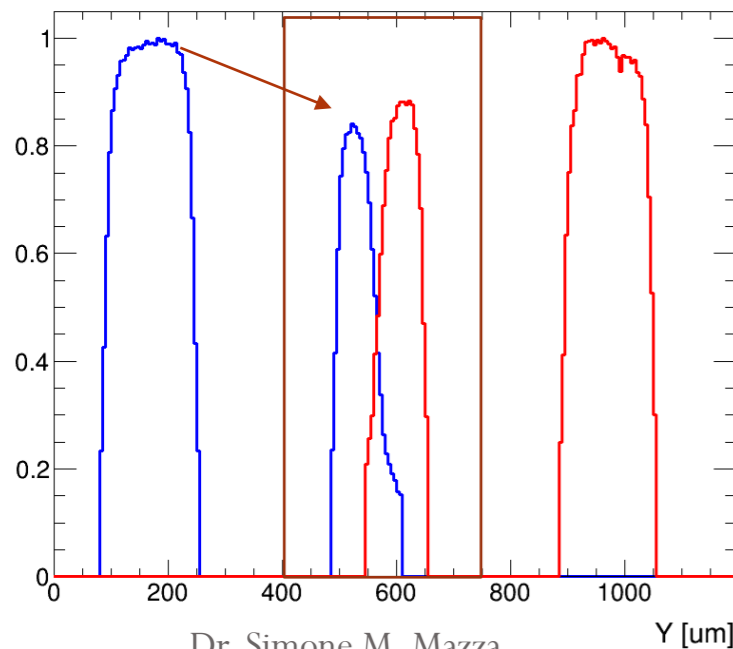


- **1D profile fractions shows a slightly lower signal next to the gap**
 - 2D simulation shows the field in the gain layer is reduced in the inter pad region
- Zoom in the inter pad region (nominal electrode gap is 30um)
 - Sum of signal show almost no reduction in the gain
 - Minor cross talk in a 50 um region between pads

The p_{max} fraction of an individual strip is defined as:

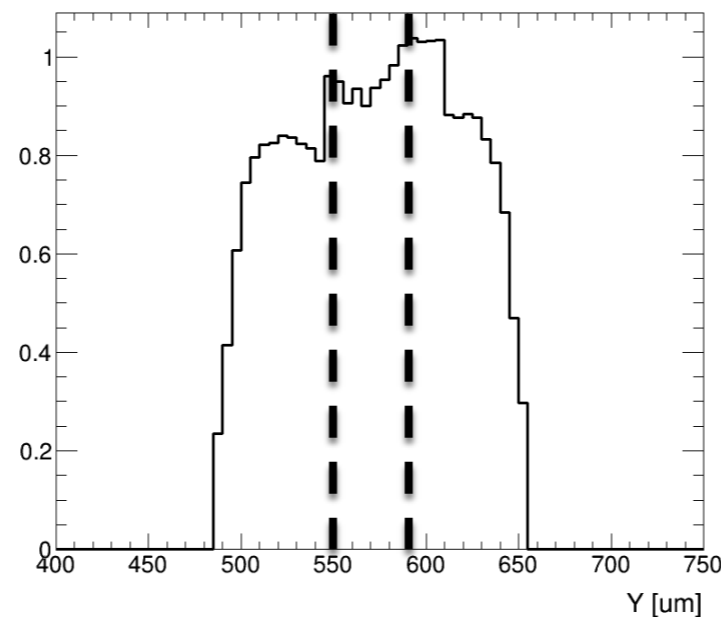
$$p_{max} \text{ fraction (channel)} = \frac{p_{max} (\text{channel})}{\sum p_{max}}$$

Normalized profile for Pad 1 and 2

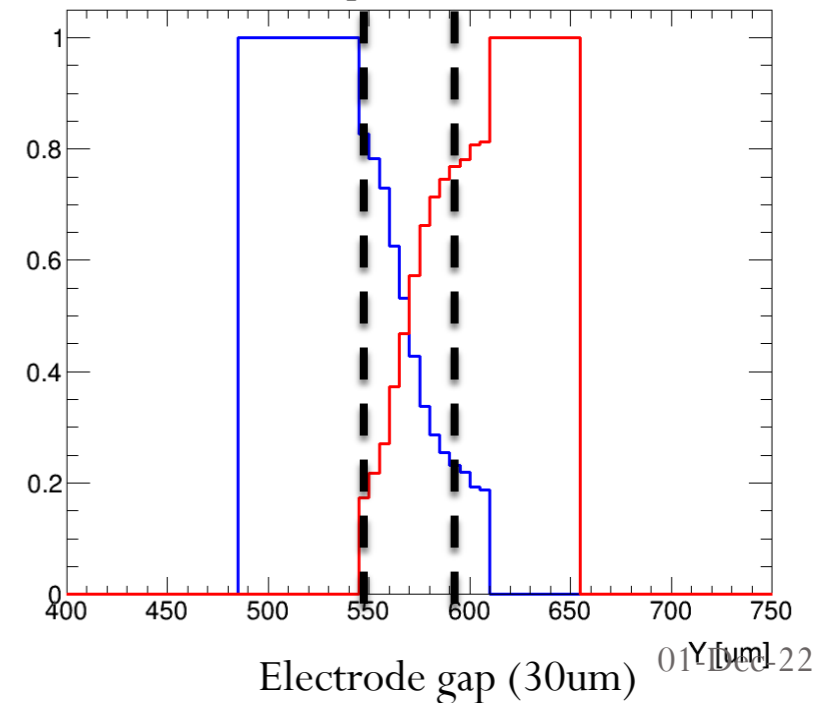


Dr. Simone M. Mazza

Normalized sum of Pad 1 and 2



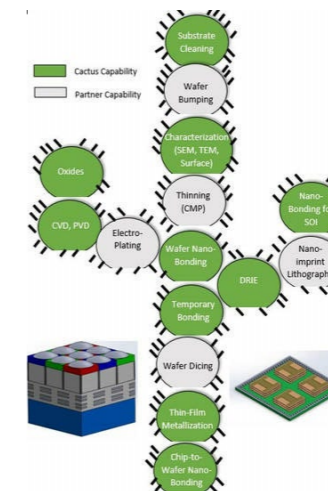
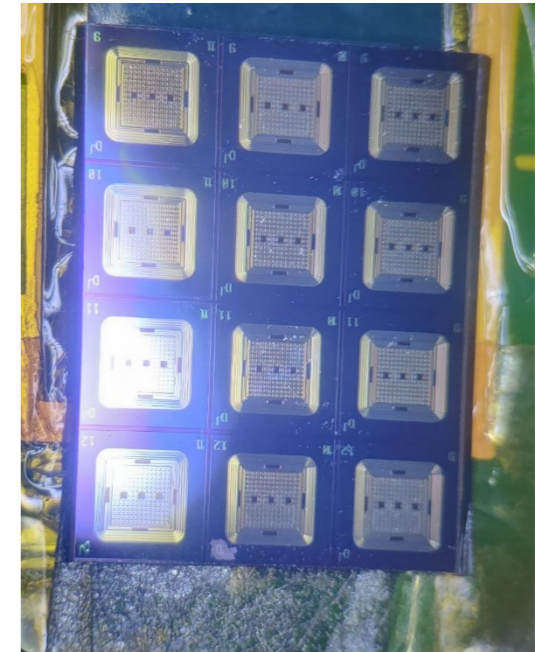
Fractional Pmax profile between Pad 1 and 2



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Conclusions

- **DJ-LGAD: a device with deep gain layer**
 - Avoid high field near the electrodes while maintaining gain
- Presented the results of first working DJ-LGAD prototype
 - **Demonstrated that the Deep-Junction can be fabricated with epitaxial growth and w2w bonding**
 - Shows very good signal/charge uniformity across channels
 - Almost no IP-gap is present between pads, small cross talk
- Future production for DJ-LGAD has already started (funded by phase II SBIR), issues to solve:
 - Very large leakage current → reduce the current to level of conventional LGAD
 - The gain is lower than conventional LGAD → optimize the doping in the future prototype
- **DJ-LGAD technology can be used as the base concept for many other new types of devices!**
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